

 INFORMATION DISCLOSURE STATEMENT BY APPLICANT PTO FORM 1449	ATTY. DOCKET NO. 11641/6	SERIAL NO. 09/705,187
	APPLICANT Kim ENOCH	
	FILING DATE November 2, 2000	RECEIVED GROUP JUN 25 2001 2:22

U. S. PATENT DOCUMENTS

TC 1700

EXAMINER INITIAL	PATENT NUMBER	PATENT DATE	NAME	CLASS	SUBCLASS	FILING DATE*
GW	3,220,960	November 30, 1965	Wichterle et al.			
	3,408,429	October 29, 1968	Wichterle			
	4,359,558	November 16, 1982	Gould et al.			
	4,404,249	September 13, 1983	Margerum et al.			
	4,408,023	October 4, 1983	Gould et al.			
	4,454,309	June 12, 1984	Gould et al.			
	4,496,535	January 29, 1985	Gould et al.			
	4,619,793	October 28, 1986	Lee			
	4,943,618	July 24, 1990	Stoy et al.			
	5,229,172	July 20, 1993	Cahalan et al.			
	5,364,662	November 15, 1994	Domenico et al.			
	5,369,012	November 29, 1994	Koontz et al.			
	5,512,131	April 30, 1996	Kumar et al.			
	5,516,527	May 14, 1996	Curatolo			

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO

OTHER DOCUMENTS

EXAMINER INITIAL	AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.	

EXAMINER <i>Kim Fey</i>	DATE CONSIDERED <i>3/26/02</i>
EXAMINER: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

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U. S. PATENT DOCUMENTS

TC 1700

EXAMINER INITIAL	PATENT NUMBER	PATENT DATE	NAME	CLASS	SUBCLASS	FILING DATE
hyp	5,514,380	May 7, 1996	Song et al.			
	5,541,304	July 30, 1996	Thompson			
	5,589,563	December 31, 1996	Ward et al.			
	5,776,748	July 7, 1998	Singhvi et al.			
	5,948,621	September 7, 1999	Turner et al.			
	6,011,082	January 4, 2000	Wang et al.			
	6,043,328	March 28, 2000	Domschke et al.			
	6,060,121	May 9, 2000	Hidber et al.			
	6,071,108	June 6, 2000	Göhr et al.			
	6,071,111	June 6, 2000	Doke et al.			
	6,085,798	July 11, 2000	Hirukawa			
	6,099,122	August 8, 2000	Chabreck et al.			
	6,106,260	August 22, 2000	Matsomoto et al.			

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO

OTHER DOCUMENTS

EXAMINER INITIAL		AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.
hyp		Yoshihito Osada and Jian-Ping Gong, "Soft and Wet Materials: Polymer Gels", Advanced Materials, 1998, Vol. 10 No. 11, pp. 827-837
hyp		David C. Duffy et al., "Patterning Electroluminescent Materials with Feature Sizes as Small as 5 μ m Using Elastomeric Membranes as Masks for Dry Lift-Off", Advanced Materials, 1999, Vol. 11 No. 7, pp. 546-552

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U. S. PATENT DOCUMENTS

EXAMINER INITIAL	PATENT NUMBER	PATENT DATE	NAME	CLASS	SUBCLASS	FILING DATE*

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO

* - Copy of the search report attached

OTHER DOCUMENTS

EXAMINER INITIAL		AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.
Kyp		Kim Enoch et al., "Solvent-Assisted Microcontact Molding: A Convenient Method for Fabricating Three-Dimensional Structures on Surfaces of Polymers", Advanced Materials, 1997, Vol. 9 No. 8, pp. 651-654
		Laurent Libioulle et al., "Contact-Inking Stamps for Microcontact Printing of Alkanethiols on Gold", Langmuir, 1999, Vol 15 No. 2, pp. 300-304
		Ryuichiro Yoda, "Elastomers for biomedical applications", J. Biomater. Sci. Polymer Edn. 1998, Vol. 9 No. 6, pp. 561-626
		André Bernard et al., "Printing Patterns of Proteins", Langmuir, 1998, Vol. 14, No. 9, pp. 2226-2228
		Hannes Kind et al., "Patterned Electroless Deposition of Copper by Microcontact Printing Palladium (II) Complexes on Titanium-Covered Surfaces", Langmuir, 2000, Vol. 16, No. 16, pp. 6387-6373
		A.S.G. Curtis et al., "Adhesion of Cells to Polystyrene Surfaces", J. Cell Biology, 1983, Vol. 97, pp. 1500-1506
		A.S.G. Curtis et al., "Substrate Hydroxylation and Cell Adhesion", J. Cell Science, 1986, Vol. 86, pp. 9-24
		Albert Folch and Mehmet Toner, "Cellular Micropatterns on Biocompatible Materials", Biotechnol. Prog., 1998, Vol. 14, pp. 388-392
✓	✓	Younan Xia and George M. Whitesides, "Soft Lithography", Angew. Chem. Ins. Ed., 1998, Vol. 37, pp. 550-575

EXAMINER	<i>Kishor Peng</i>	DATE CONSIDERED	3/6/02
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SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT BY APPLICANT <div style="text-align: right; margin-top: -20px;">  FEB 27 2002 </div>	ATTY. DOCKET NO. 11641/6	SERIAL NO. 09/705,187
	APPLICANT Enoch KIM	
	FILING DATE November 2, 2000	GROUP 1714 1712

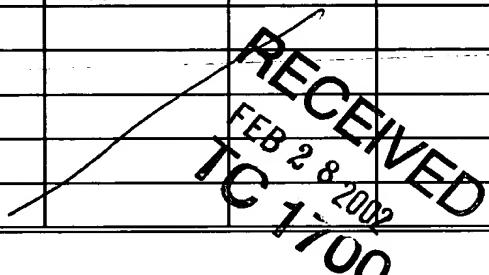
U. S. PATENT DOCUMENTS

EXAMINER INITIAL	PATENT NUMBER	PATENT DATE	NAME	CLASS	SUBCLASS	FILING DATE
RIP	5,691,479*	05 October 1999	Reeves et al.			
	5,965,237*	12 October 1999	Bruin et al.			
↓	5,129,807*	14 July 1992	Oriez et al.			

* - Copy of the search report attached

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OTHER DOCUMENTS

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